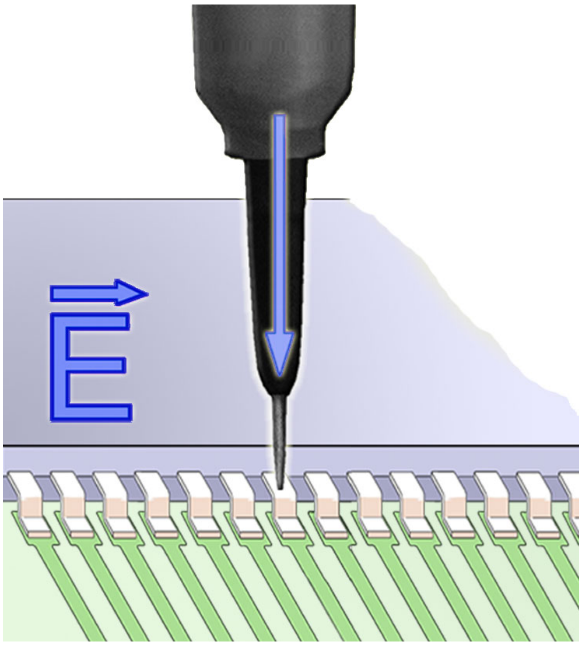
ES 08D-h

E-Field Source

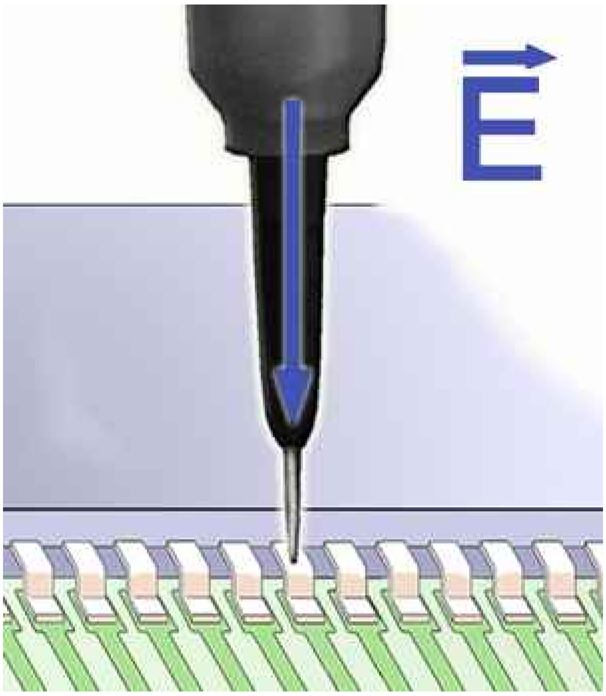


Short description

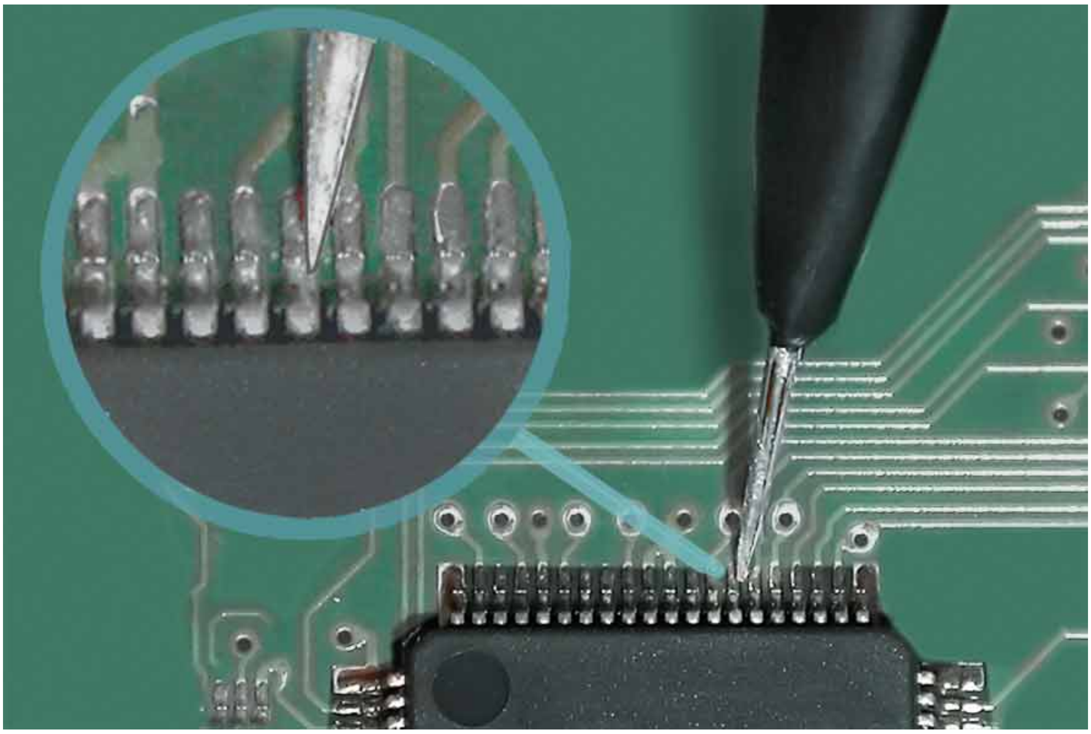
The ES 08-h E field source is a test probe to determine the sensibility of an IC pin or a line. For measurements the probe must be in contact with a pin / conducting path and, because of its changing interference pulse intensities from the EFT/burst generator or TS 23 Pulse Generator, the sensitivity of the pin / conducting path can be detected. Inside the field source the interference pulse is coupled capacitively on the tip. Thus, useful signals are not loaded.

The field source is powered by an EFT/burst generator or TS 23 Pulse Generator. The generator is connected to the 4.4 kV, high voltage resistant SMB plug of the field source via a high-voltage cable (HV SMB 1 m, SMB-BNC 1 m, or GK 0.7 m SMB-SMB).

Measuring principles



Application with ES 08D-h



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